| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 1 | BRS | 2 | "2004015409" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/14 13:36 | |
| 2 | BRS | 5 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3) with troubleshoot$3 and micro-fabrication | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 13:58 | |
| 3 | BRS | 1324 | 700/117,118,183,185.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/18 17:16 | |
| 4 | BRS | 1296 | 700/121.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/14 13:40 | |
| 5 | BRS | 440 | 714/46.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/14 13:41 | |
| 6 | BRS | 6 | "6635872" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/14 14:47 | |

| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 7 | IS&R | 2 | ("5656811").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/14 13:43 | |
| 8 | BRS | 82 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3) with troubleshoot$3 and (micro-fabrication or fabrication) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/14 13:58 | |
| 9 | IS&R | 2 | ("5938424").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/14 13:54 | |

| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 10 | BRS | 82 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with troubleshoot$3 and (micro-fabrication or fabrication) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:53 | |
| 11 | BRS | 2 | "20030120436" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/14 13:58 | |
| 12 | BRS | 8391 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:01 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 13 BRS | 60 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charged with beam$1 and software | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:02 | |
| 14 BRS | 5 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charged with beam$1 and software with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:03 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|-----------|----------|
| 15 BRS | 7 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with beam$1 and software with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:03 | |
| 16 BRS | 21 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with beam$1 and (program$4 or software$1) with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:30 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 17 15 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 and (program$4 or software$1) with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:04 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 18<br>5 | (analy$4 or diagnos$3)<br>with (defect$1 or error$1<br>or malfunction$2 or<br>problem$1 or fault$1 or<br>fail$3 or anomal$3 or<br>trouble$1) with<br>(semiconductor$1 or<br>wafer$1 or IC$1 or<br>(integrated adj circuit$1)<br>or chip$1 or die$1) and<br>charg$3 with particle$1<br>with beam$1 and (program$4<br>or software$1 or cod$3)<br>with execut$3 and user$1<br>with interface | US-PGPUB;<br>USPAT; EPO;<br>JPO; DERWENT;<br>IBM_TDB | 2005/07/14<br>17:47 | |

| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 19 | BRS | 1 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (tow or dual) with charg$3 with beam$1 and (program$4 or software$1) with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:33 | |
| 20 | BRS | 3 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (tow or dual) with charg$3 with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:33 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 21 | IS&R | 2 | ("6635872").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:47 | |
| 22 | BRS | 0 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with troubleshoot$3 and (micro-fabrication or fabrication) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and high with resolution with image$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:54 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 23 BRS | 2 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with troubleshoot$3 and (micro-fabrication or fabrication) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and high with resolution with imag$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:56 | |
| 24 BRS | 1173 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (micro-fabrication or fabrication) and high with resolution with imag$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:56 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 184 | (troubleshoot$3 or inspect$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (micro-fabrication or fabrication) and high with resolution with imag$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:57 | |
| 25 | | | | | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 26<br>70 | (troubleshoot$3 or inspect$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (micro-fabrication or fabrication) and high with resolution with imag$3 and defect$1 with (file$1 dor database) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:58 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 27 BRS | 1 | (troubleshoot$3 or inspect$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (micro-fabrication or fabrication) and high with resolution with imag$3 and initial$2 with defect$1 with (file$1 dor database) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 14:58 | |
| 28 BRS | 107 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) and chemical$2 with analys$4 with surface$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:32 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 29 BRS | 4 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and chemical$2 with analys$4 with exposed with surface$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:34 | |
| 30 BRS | 11 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or IC$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and chemical$2 with analys$4 with expos$$3 with surface$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:38 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| 31 BRS | 7 | (analy$4 or diagnos$3). with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and EDS with tool$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:41 | |
| 32 BRS | 1 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and cross with section$2 with three with dimension and EDS with tool$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:41 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 33 | BRS 1 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and cross with section$2 with dimension and EDS with tool$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:42 | |
| 34 | BRS 1 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (cross-section$2 or (cross with section$2)) with dimension and EDS | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:42 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 1 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (cross-section$2 or (cross with section$2)) with (3-d mor dimension$1) and EDS | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:43 | |
| BRS | 142 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (cross-section$2 or (cross with section$2)) with (3-d mor dimension$1) and EDS | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:06 | |

| Type | | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 37 | BRS | 1 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (cross-section$2 or (cross with section$2)) with (3-d mor dimension$1) with EDS | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:43 | |
| 38 | BRS | 3 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (cross-section$2 or (cross with section$2)) with (3-d mor dimension$1) same EDS | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:45 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 39 BRS | 3 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and cut$4 with (cross-section$2 or (cross with section$2)) with (3-d mor dimension$1) and EDS | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 15:53 | |
| 40 BRS | 3 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and cut$4 with (cross-section$2 or (cross with section$2)) with (3-d or dimension$1 or three-dimension$2) and EDS | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 16:21 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| 41 | BRS | 307 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and chemical$2 with analy$4 with surface$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 17:29 | |
| 42 | BRS | 46 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) with chemical$2 with analy$4 with surface$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 17:30 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 43 | BRS | 4 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or chip$1 or die$1) with (integrated adj circuit$1) with chemical$2 with analys$4 with expos$3 with surface$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 17:32 | |
| 44 | BRS | 4 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or chip$1 or die$1) with (integrated adj circuit$1) with chemical$2 adj analys$4 with surface$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 17:32 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 45 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and two with charg$3 with particle$1 with beam$1 and (program$4 or software$1 or cod$3) with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/14 17:49 | |

3

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 46<br>5 | (analy$4 or diagnos$3)<br>with (defect$1 or error$1<br>or malfunction$2 or<br>problem$1 or fault$1 or<br>fail$3 or anomal$3 or<br>trouble$1) with<br>(semiconductor$1 or<br>wafer$1 or IC$1 or<br>(integrated adj circuit$1)<br>or chip$1 or die$1) and<br>charg$3 with particle$1<br>with beams and (program$4<br>or software$1 or cod$3)<br>with execut$3 | US-PGPUB;<br>USPAT; EPO;<br>JPO; DERWENT;<br>IBM_TDB | 2005/07/15<br>09:18 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 47<br>2 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) same charg$3 with particle$1 with beams and (program$4 or software$1 or cod$3) with execut$3 | US-PGPUB;<br>USPAT; EPO;<br>JPO; DERWENT;<br>IBM_TDB | 2005/07/15<br>09:22 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 711 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 devices with beams and (program$4 or software$1 or cod$3) with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:04 | |

48

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 49<br>5 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with device$1 with beams and (program$4 or software$1 or cod$3) with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 09:27 | |

| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 50 | BRS | 2 | (analys$4 or diagnos$$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (dual or two) with charg$3 with particle$1 with beams and (program$4 or software$1 or cod$3) with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 09:43 | |
| 51 | BRS | 2 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (dual or two) with charg$3 with particle$1 with beams | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 09:44 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 52 BRS | 12 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) same (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (dual or two) with charg$3 with particle$1 with beams | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 09:45 | |
| 53 BRS | 0 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) same (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and dual with charg$3, with particle$1 with beams | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 09:45 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 54 BRS | 5 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) same (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and dual with charg$3 with particle$1 with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 09:46 | |
| 55 BRS | 6 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) same (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) and dual same charg$3 with particle$1 with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 09:50 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 56 BRS | 2 | jp-11213935-$.did. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/15 09:48 | |
| 57 BRS | 45 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) same (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (two or dual) with charg$3 with particle$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 09:56 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 58 BRS | 12 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) same (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (two or dual) adj beams and charg$3 with particle$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:00 | |
| 59 BRS | 5 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) and chip$1 or die$1) and charg$3 with particle$1 with beams and (program$4 or software$1 or cod$3) with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:06 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 1 60 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beams and (program$4 or software$1 or cod$3) with execut$3 and user$1 with (interface or communicat$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:07 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 5 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$ and (program$4 or software$1 or cod$3) with execut$3 and user$1. with (interface or communicat$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:15 | |

61

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 62 BRS | 58 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beams | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:16 | |
| 63 BRS | 16 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or IC$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beams and user$1 with (interface or communicat$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:17 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS 18 | 64 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 and (two or dual) with beam$1 and user$1 with (interface or communicat$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:20 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 65<br>16 | (analy$4 or diagnos$3)<br>with (defect$1 or error$1<br>or malfunction$2 or<br>problem$1 or fault$1 or<br>fail$3 or anomal$3 or<br>trouble$1) with<br>(semiconductor$1 or<br>wafer$1 or IC$1 or<br>(integrated adj circuit$1)<br>or chip$1 or die$1) and<br>charg$3 with particle$1<br>with beam$1 and (two or<br>dual) adj beam$1 and<br>user$1 with (interface or<br>communicat$3) | US-PGPUB;<br>USPAT; EPO;<br>JPO; DERWENT;<br>IBM_TDB | 2005/07/15<br>10:25 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 66<br>0 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 and (two or dual) adj beam$1 and user$1 with (interface or communicat$3) and computer with job$1 | US-PGPUB;<br>USPAT; EPO;<br>JPO; DERWENT;<br>IBM_TDB | 2005/07/15<br>10:26 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 67 16 | (analy$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 and (two or dual) adj beam$1 and user$1 with (interface or communicat$3) and computer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:26 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| | | (analy$4 or diagnos$$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 and (two or dual) adj beam$1 and user$1 with (interface or communicat$3) with computer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 16:12 | |
| BRS | 16 | | | | |

68

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 69 | 1 | (analy$4 or diagnos$$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 and (two or dual) adj beam$1 and user$1.with (interface or communicat$3) with computer and receiv$3 with request$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 10:34 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 44 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 and ion with mill$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/15 16:45 | |
| 70 | | | | | |
| IS&R | 2 | ("6539106").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB | 2005/07/15 17:02 | |
| 71 | | | | | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 72 | BRS | 627 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (calibrat$3 or compensat43 or adjust$3) with imag$3 with value$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:07 | |
| 73 | BRS | 773 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (calibrat$3 or compensat$3 or adjust$3) with imag$3 with value$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:07 | |

| ` | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|------|------|-------------|-----|-----------|----------|
| 74 | BRS | 53 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (calibrat$3 or compensat$3 or adjust$3) with imag$3 with value$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:08 | |
| 75 | BRS | 1 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (calibrat$3 or compensat$3 or adjust$3) with charged particle with beam with parameter$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:09 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| 76 BRS | 1 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (calibrat$3 or compensat$3 or adjust$3) with parameters$1 same charged with particle with beam | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:09 | |
| 77 BRS | 17 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (calibrat$3 or compensat$3 or adjust$3) with parameters$1 and charged with particle with beam | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:09 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 78 BRS | 17 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (calibrat$3 or compensat$3 or adjust$3) with parameter$1 and charged with particle with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:09 | |
| 79 BRS | 1 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (calibrat$3 or compensat$3 or adjust$3) with parameter$1 and charged with particle with beam$1 and relocat$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:43 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 80 BRS | 221 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and chemical with analysis | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 12:23 | |
| 81 BRS | 11 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and SEM with chemical with analysis | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 10:44 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 82 BRS | 2 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and user$1 with (interface$1 or communication$1) with defin$3 with (condition$1 or state$1 or status$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 12:32 | |
| 83 BRS | 1 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) and pause same user$1 with (interface$1 or communication$1) with defin$3 with (condition$1 or state$1 or status$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 12:31 | |

| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 84 | BRS | 1 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and pause same user$1 with (interface$1 or communication$1) with defin$3 with (condition$1 or state$1 or status$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 12:32 | |
| 85 | BRS | 65 | (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and pause with user$1 with (interface$1 or communication$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 12:32 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 1 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and pause with user$1 with (interface$1 or communication$1) and defin$3 with (condition$1 or state$3 or status$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 12:32 | |
| BRS | 3 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and pause with user$1 with (interface$1 or communication$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 13:50 | |

| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 88 | IS&R | 2 | ("6539106").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 12:59 | |
| 89 | BRS | 320 | analys$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and ion with beam$1 with electron with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 13:51 | |
| 90 | BRS | 401 | analys$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and ion with beam$1 with electr$4 with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 13:51 | |

| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 91 | BRS | 5 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and ion with beam$1 with mill$3 with object$1 and electr$4 with beam$1 with imag$3 with object$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:02 | |
| 92 | BRS | 1 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and ion with beam$1 with mill$3 and electr$4 with beam$1 with imag$3 and computer with execut$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 14:04 | |

| | Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|---|
| 93 | BRS | 5 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and ion with beam$1 with mill$3 and electr$4 with beam$1 with imag$3 and computer and user$1 with (interface$1 or communicat$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 14:06 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS 3 | 94 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and ion with beam$1 with mill$3 and electr$4 with beam$1 with imag$3 and computer and user$1 with (interface$1 or communicat$3) and (delet$3 or remov$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 14:06 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 39 | analys$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or chip$1 or die$1) or (integrated adj circuit$1) and (adjust$3 or calibrat$3 or compensat$3) with imag$3 with magnif$7 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:03 | |
| BRS | 13 | analys$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or chip$1 or die$1) or (integrated adj circuit$1) and (adjust$3 or calibrat$3 or compensat$3) with imag$3 with magnif$7 and align$4 with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:17 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 97 5 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3) with imag$3 with magnif$7 and align$4 with beam$1 and (!relocat$3 or locat$3) with previous$2 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:07 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 98<br>5 | analys$4 with (defect$1 or<br>error$1 or malfunction$2<br>or problem$1 or fault$1 or<br>fail$3 or anomal$3 or<br>trouble$1) with<br>(semiconductor$1 or<br>wafer$1 or IC$1 or<br>(integrated adj circuit$1)<br>or chip$1 or die$1) and<br>(adjust$3 or calibrat$3 or<br>compensat$3) with imag$3<br>with magnif$7 and align$4<br>with beam$1 and (relocat$3<br>or locat$3 or re-locat$3)<br>with previous$2 with<br>(defect$1 or error$1 or<br>malfunction$2 or problem$1<br>or fault$1 or fail$3 or<br>anomal$3 or trouble$1) | US-PGPUB;<br>USPAT; EPO;<br>JPO; DERWENT;<br>IBM_TDB | 2005/07/18<br>15:08 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 99 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or chip$1 or die$1) or (integrated adj circuit$1) (adjust$3 or calibrat$3 or compensat$3) with imag$3 with magnif$7 and align$4 with beam$1 and (relocat$3 or locat$3 or re-locat$3) with previous$2 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) and (adjust$3 or calibrat$3 or compensat$3) with charged with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:20 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| 100 BRS | 11 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3) with charged with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:09 | |
| 101 BRS | 1 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3) with charged with beam$1 with parameter$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:09 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| 102 BRS | 2 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3) with imag$3 with magnif$7 and align$4 with beam$1 and (adjust$3 or calibrat$3 or compensat$3) with charged with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:17 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| BRS | 103 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3) with imag$3 with magnif$7 and align$4 with beam$1 and (adjust$3 or calibrat$3 or compensat$3) with charg$3 with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:17 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 104 BRS | 5 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3) with image$3 with magnif$7 and align$4 with beam$1 and (relocat$3 or locat$3 or re-locat$3) with previous$2 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:21 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 105 BRS | 1 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3 or modify$3 or chang$3) with imag$3 with magnif$7 and align$4 with beam$1 with parameter$1 and (relocat$3 or locat$3 or re-locat$3) with previous$2 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:22 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|-----------|----------|
| 106 BRS | 5 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3 or modify$3 or chang$3) with imag$3 with magnif$7 and (relocat$3 or locat$3 or re-locat$3) with previous$2 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:23 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 107<br>5 | analys$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fails$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) or (adjust$3 or calibrat$3 or compensat$3 or modify$3 or chang$3) with imag$3 with magnif$7 and (relocat$3 or locat$3 or re-locat$3) with (histor$6 or previous$2) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fails$3 or anomal$3 or trouble$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:24 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| BRS | 108 | analy$4 with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3 or modify$3 or chang$3) with imag$3 with magnif$7 and (relocat$3 or locat$3 or re-locat$3) with (histor$6 or previous$2) with imag$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:24 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|-----------|----------|
| BRS | 6 | analy$4 same (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and (adjust$3 or calibrat$3 or compensat$3 or modify$3 or chang$3) with imag$3 with magnif$7 and (relocat$3 or locat$3 or re-locat$3) with (histor$6 or previous$2) with imag$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:26 | |

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| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|-----------|----------|
| 110 BRS | 1 | analy$4 same (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charged with beam$1 and (adjust$3 or calibrat$3 or compensat$3 or modify$3 or chang$3) with imag$3 with magnif$7 and (relocat$3 or locat$3 or re-locat$3) with (histor$6 or previous$2) with imag$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:27 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 111 BRS | 6 | analy$4 same (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charged with beam$1 and control$5 with stage$1 with receiv$3 with (position$3 or locat$4) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:48 | |
| 112 BRS | 2 | analy$4 same (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charged with beam$1 and control$5 with stage$1 with receiv$3 with (position$3 or locat$4) with beam$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 15:48 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|------|------|-------------|-----|------------|----------|
| 113 BRS | 17 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 with (two or dual) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 16:41 | |
| 114 BRS | 1 | (analys$4 or diagnos$3) with (defect$1 or error$1 or malfunction$2 or problem$1 or fault$1 or fail$3 or anomal$3 or trouble$1) with (semiconductor$1 or IC$1 or wafer$1 or IC$1 or (integrated adj circuit$1) or chip$1 or die$1) and charg$3 with particle$1 with beam$1 with (two or dual) and path$1 with travel$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | 2005/07/18 16:43 | |

| Type | Hits | Search Text | DBs | Time Stamp | Comments |
|---|---|---|---|---|---|
| 115 BRS | 807 | 702/183.ccls. | US-PGPUB;<br>USPAT; EPO;<br>JPO; DERWENT;<br>IBM TDB | 2005/07/18<br>17:15 | |
| 116 BRS | 2102 | 702/117,118,183,185.ccls. | US-PGPUB;<br>USPAT; EPO;<br>JPO; DERWENT;<br>IBM TDB | 2005/07/18<br>17:16 | |